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Application/Control No.	Applicant(s)/Patent under Reexamination
10/683,712	BOGNER ET AL.
Examiner	Art Unit
Joseph Nguyen	2815

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Class	Subclass	Date	Examiner
257	676, 684	10/12/2007	JN
257	706, 98	10/12/2007	JN

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Class	Subclass	Date	Examiner
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